International Conferences organized by the CSCA

AMEX I, II. The series of international crystallographic conferences organized by the Crystallographic Association started with "**Advanced Methods in X-ray Structure Analysis**" (J. Fiala, J. Hašek, R. erný, V. Valvoda, Karlovy Vary in **1987**) and the AMEX conference organized in Pyramida, Praha **1990** by V. Pet í ek, J. Fiala, V. Valvoda, R. erný, R. Kužel, J. Hašek. Both conferences brought nearly 200 participants including several famous crystallographers to Czechoslovakia.





The 18th European Crystallographic Meeting in August 16-20, 1998 took place mainly buildings of the Czech Technical University in Prague. 1 059 participants came from 39 countries all over the world. The largest number of them was from Germany (185), United Kingdom (109), Russia (80), France (80), Czech Republic (70), Poland (50), Italy (41), USA (41) and Sweden (40). The program consisted of 18 plenary lectures, and 240 lectures presented

in 48 microsymposia organized in 6 parallel streams corresponding to 6 focus areas: Structure in Physics and Applied Crystallography, Materials Science, Structural Aspects in Chemistry, Chemical Crystallography, Structure and Function of Biological Systems, Advanced Methods for Structural Investigations and Methods for Structure Determination in Biology, General Crystallography and Discussion Meetings. The ECM was preceded by 5 workshops on symmetry of crystals, methods of crystal structure determination, use of databases. 558 contributions were presented in a poster form. 200 students were supported from different sources.

The session to the 50th anniversary of the IUCr involving four plenary lectures on the history of IUCr and future perspectives of crystallography took place in the Prague's State Opera and was chaired by the president of the IUCr - Prof. Ted Baker.

Cultural programme included concert to the 25th anniversary of the ECM in the National Museum, crystallographic exhibition Structure of the Microworld (for public opened three months after the conference); concert to the 650th anniversary of the Charles University in Prague; the K ižík's night colourful fountains with music performances, trips to different destinations around Prague and farewell party.

The Web pages www.xray.cz/ecm still contain nearly all the information, e.g. list of participants, complete conference programme, all the abstracts. The post-conference book "Advances in Structure Analysis" with long reviewed selected papers was published by the CSCA. The conference CD-ROM with useful software (still available from the above pages) was published after the conference as well.



ICDD workshop at AMEX





H. D. Flack



ECM-18, session Structure and function in molecular biology, on the left J. Hašek, the conference chairman (photos from ECM, Bill Duax).

Size

DOAHA

The idea of the **Size-Strain conferences** was introduced by the long-time vicepresident of the CSCA Prof. Jaroslav Fiala and should emphasize the role of the socalled real structure of materials and its characterization by X-ray diffraction. The first conference was organized by the CSCA in August 1995 in Liptovský Mikuláš, Slovakia (P. Šutta). It was followed by the book published in the IUCr Oxford series edited by R. Snyder, H.J. Bunge and J. Fiala: Defect and Microstructure Analysis by Diffraction (Oxford University Press, NY, 1999) and the tradition of the conference has been established. The next meetings were held in November 1998 in Freiberg,

Germany and in Trento (2001), Italy. This year already the 6^{th} Size-Strain meeting is planned in France. The conferences are devoted to the problems of real structure of polycrystalline materials mainly but not only by diffraction methods. Usually about 100 or more participants take part and this was true also in 2004 when the conference preceded EPDIC in Prague.





The **EPDIC IX** was organized in September 2004 and started with workshop organized by Lachlan M Cranswick on size-strain and phase analysis software. Traditional EPDIC scheme with six plenary lectures and two parallel sessions was applied. The posters were displayed during the whole conference as usual. Topics were the following: structure solution from powder diffraction - methods and application, stress, strain and texture analysis, neutron diffraction - instruments and applications, phase transitions, non-ambient conditions, phase analysis, structure and properties of bio-materials, nanocrystal-line materials, metals and alloys, minerals, thin films, techniques and instruments, indexing powder patterns and software.

The conference was opened with a welcome evening in the Prague Congress Center by the traditional EPDIC award lecture followed by music performance of the Z-band - mixed voice Prague children choir. On the last day of the conference, a special train trip to Pilsen was organized. Participants had a dinner directly in the famous Pilsen brewery and took part at the excursion there. More than 320 participants arrived from 36 countries of Europe, North and South America, Africa, Asia and Australia. About hundred six-pages papers were published in *Zeitschrift für Kristallographie* after the conference.





XTOP 2004

The **7th Biennial Conference on High Resolution X–Ray Diffraction and Imaging – XTOP 2004** - was held in Congress Centre in Pr honice, one of suburbs of Praha, from September 7–10, 2004. The conferences of these series provide a wide range of topics including theory of X-ray scattering, high-resolution, diffraction, reflection, grazingincidence scattering, thin films and nanostructures, topography, imaging techniques and instrumentation. Preconference tutorial lectures were presented by experts in the field: J. Härtwig, J. Stangl, U. Pietsch, and J. Hrdý.

The scientific programme consisted of 9 invited talks, 34 oral presentations and 104 posters. During one session,





Professor Andrew Lang, a honorary guest, one of the pioneers of X-ray topography, who gave his name of the popular topographic technique, celebrated his 80th birthday. Reviewed papers were published in a special issue of *Journal of Physics D*. In total 147 official delegates and 8 accompanying persons from 16 countries of three continents attended this conference.